

## **Notice of References Cited**

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Applicant(s)/Patent Under Reexam  
Madrid

Examiner  
Edward Wojciechowicz

Art Unit  
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### U.S. PATENT DOCUMENTS

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
A	2002/0074147	6/2002	Tan et al	257	668
B	2002/0050912	5/2002	Shrier et al	257	668
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